

High Resolution Electron-Microscope Studies on a Quenched $(\text{Ni}_{0.5}\text{Cr}_{0.5})_7\text{Nb}_6$ Alloy

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Crystals of a $(\text{Ni}_{0.5}\text{Cr}_{0.5})_7\text{Nb}_6$ alloy have been studied with a high-resolution electron microscope. Crystals of the Friauf-Laves and μ phases were identified in the sample, which is in agreement with the X-ray powder pattern. Planar defects of different kinds were easily and frequently observed. The structural model of defects have been derived via chemical twinning and intergrowth operations.

Introduction

High-resolution electron microscopy has been very useful in the study of the real structure of crystals on an atomic scale. Two-dimensional lattice images recorded with a high-resolution electron microscope not only give the average structure, but also reveal the different kinds of structural defects. The high-resolution electron-microscopy technique has been applied to the study of some of the so-called tetrahedrally close-packed alloy structures. Two-dimensional lattice images of regular and defect structures were found for the μ phase in Fe-Mo and Mo-Co-Si alloys with a high-resolution electron microscope (1, 2). Different crystallographic operations and intergrowth have been used to describe the so-called tetrahedrally close-packed alloy structures (3). This concept will be used here since it is general and nearly exact in

deriving crystal structures and their planar defects. The Mg-based pseudo-binary Friauf-Laves phases have been extensively investigated and several stacking variants and defects have been found by Y. Komura *et al.* (4).

The aim of the present investigation was to study the nature of the defect structures of the Friauf-Laves and μ phases as they occur in the $(\text{Ni}_{0.5}\text{Cr}_{0.5})_7\text{Nb}_6$ alloy with a high-resolution electron microscope.

Experimental Procedure

Alloys having the nominal composition $(\text{Ni}_{0.5}\text{Cr}_{0.5})_7\text{Nb}_6$ were prepared by melting weighed amounts of pure Nb, Ni, and Cr in an argon-filled electric arc furnace. The sample was sealed in a silica tube, which was evacuated and annealed at 1055°C for 24 hr. The powder pattern of the sample obtained in a Guinier-Hägg focusing camera using $\text{CuK}\alpha$ radiation showed the presence of the Friauf-Laves and μ phases.

The crystals were crushed and ground in

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a hardened steel mortar and then thin fragments were collected on a holey carbon film supported on a copper grid. The perforated carbon films with the sample were transferred to a JEOL 200CX electron microscope, equipped with a top entry high-resolution $\pm 10^\circ$ double tilting stage and operated at 200 kV. Crystals of the Friauf–Laves and μ phase were identified in the sample, which is in good agreement with the X-ray powder pattern. Using selected area diffraction and a goniometer stage, the orientation of the crystals were adjusted, so that the [110] of the hexagonal cell for Friauf–Laves and μ phase was parallel to the incident electron beam. The alignment procedure had to be repeated for different parts of the crystal, since a slight bending is always present. High-resolution lattice images were recorded at a magnification of 690,000, using

an objective aperture corresponding to a radius of 0.34 \AA^{-1} in the diffraction pattern. The computer simulated images were obtained using the multislice method with a program written by M. A. O'Keefe.

Results

The MgZn_2 -type Friauf–Laves Phase

The crystal structure of the Friauf–Laves phase was found by Friauf (5) and Laves (6). The atomic arrangement in the MgZn_2 -type Friauf–Laves structure projected along [110] can be described as consisting of uncentered trigonal bipyramids sharing edges and corners generating pentagonal antiprisms. This can be seen in the inserted drawing in the high-resolution micrograph (Fig. 1) of a perfectly ordered structure of

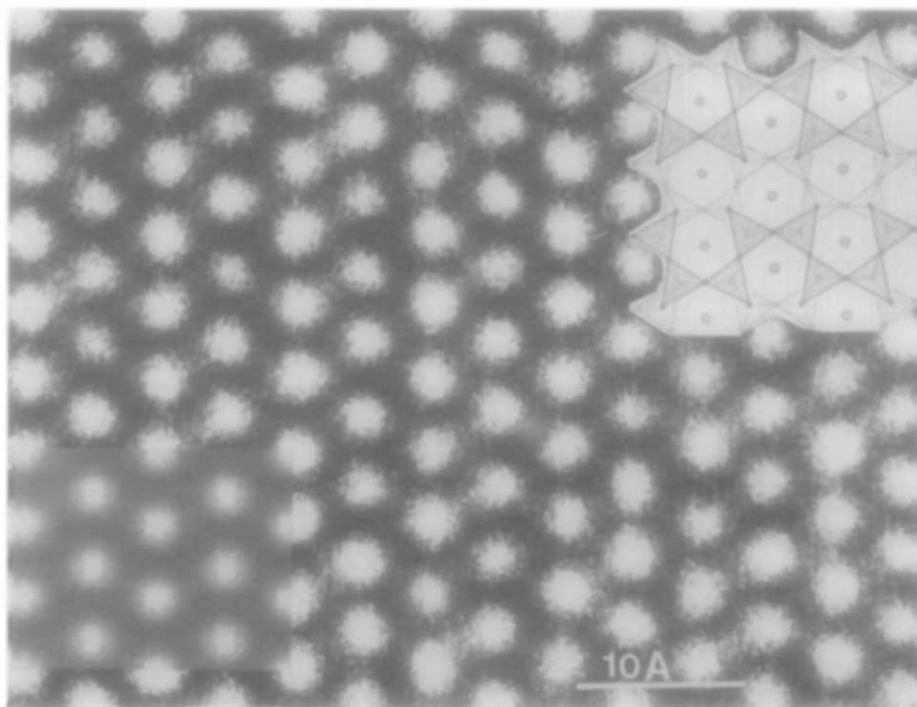


FIG. 1. Crystal structure image (CSI) of a perfectly ordered $(\text{Ni,Cr})_7\text{Nb}_6$ crystal with MgZn_2 structure in the [110] direction. Crystal structure drawing and calculated image are inserted in upper right and lower left corners, respectively.

MgZn_2 type in the [110] direction. The white dots correspond to the position of the pentagonal antiprisms, which was confirmed by calculation with the multislice method; see insertion in lower left corner of Fig. 1. The following parameters were used for the calculation.

Spherical aberration coefficient = 1.2 mm, slice thickness = 4.861 Å, the focus spread due to chromatic aberration = 30 Å, incident beam convergence = 0.6 mrad, and the number of diffracted beams included in the dynamical diffraction calculation = 1027. The images were computed for a range -500 to -800 Å. The best agreement between experimental and calculated image was made with a defocus of -600 Å and a crystal thickness of 38.9 Å and this was used to produce the inserted image.

Planar defects of different kinds were easily and frequently observed. Figure 2 shows a two-dimensional crystal structure image of a well-resolved planar defect in MgZn_2 -type Friauf-Laves phase structure.

On the basis of the correlation of the image contrast with structural features, the structure of the defects can be derived from the observed image contrast. A structural model of the defect is inserted in Fig. 2. The structure of the defect can be described as an intergrowth between Friauf-Laves and three sheets of μ -phase-type structure (see below). Such an intergrowth structure has not yet been found in crystals of the Friauf-Laves phase structure. The crystal structure image in Fig. 3 shows another kind of defect, revealing an intergrowth between Friauf-Laves and four sheets of double-twinned μ -phase structural type. A model of the atomic arrangement of the defect area is shown in the figure, where the arrows show the twin-planes.

The μ Phase

The structure of the μ phase was first determined by Westgren (7) and was later refined for the isotypic Co_7Mo_6 (8). The μ -phase structure can be seen as an

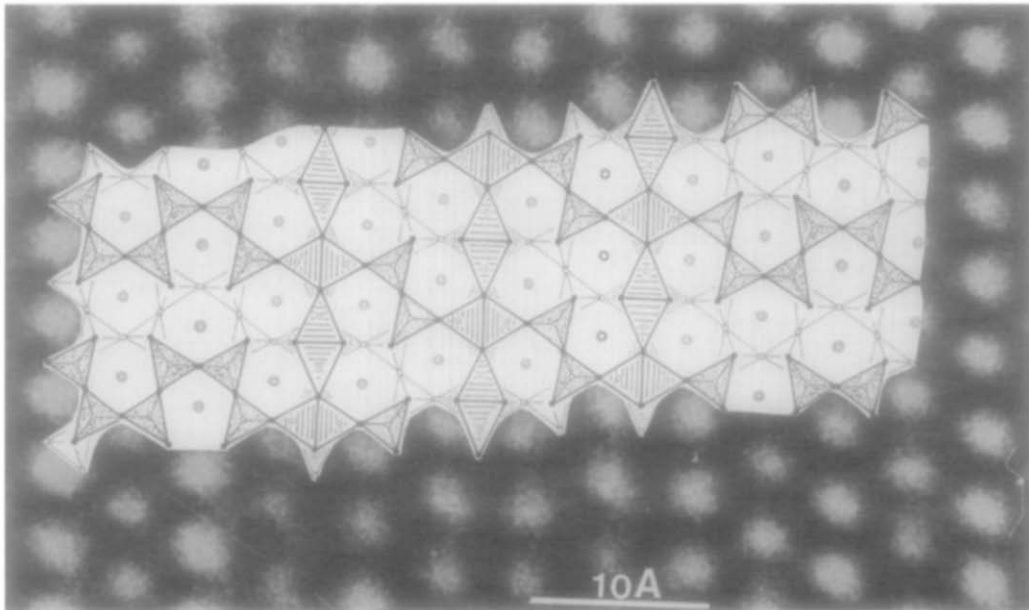


FIG. 2. $(\text{Ni,Cr})_3\text{Nb}_6$ crystal with MgZn_2 structure, but with three slabs of the μ -phase structure penetrating the crystal.

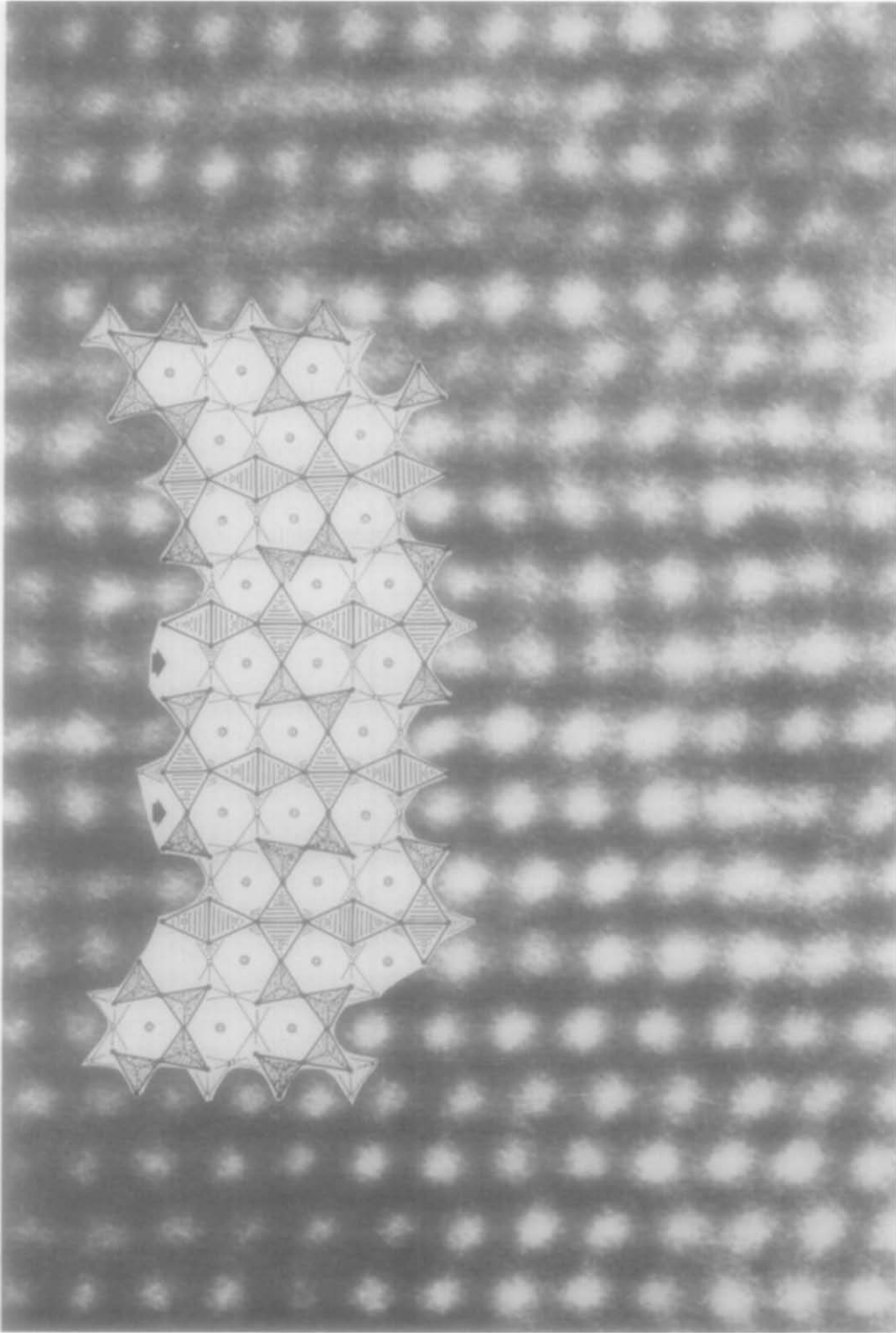


FIG. 3. CSI of (Ni, Cr)₇Nb₆ crystal with MgZn₂ structure with an intergrowth of twinned μ-phase structure or the Cs₂K₆ structure. Arrows indicate twin-planes.

intergrowth of sheets of the Zr_4Al_3 , viewed along $[110]$, and $MgCu_2$ structure projected along $[110]$ (3). An interesting variation of the μ -phase structure has been found by A. Simon *et al.* (9) for the structure of Cs_6K_7 .

The crystal structure image of a μ -phase crystal together with the structure drawing is shown in Fig. 4. The white dots indicate the sites of the pentagonal antiprisms generated by the structure. A calculated image, using the multislice method as mentioned above (also inserted in Fig. 4), agrees well with the experimental result.

In a previous paper (2) it was reported that the μ -phase structure could accommodate disorder in four simple ways, viz., twin operation and three kinds of intergrowth with a $MgCu_2$, $MgZn_2$, and Zr_4Al_3 structural type. The high-resolution image

of the present observations has enabled us to obtain much more direct evidence of the presence and structure of defects of the μ phase. Figure 5 shows a crystal structure image of a twin defect with the atomic arrangement given in the inserted drawing. If a double twin operation is carried out in the two adjacent planes in $[001]$ on the structure, the atomic arrangement of this type of defect can be achieved. Another way to describe this is obtained if the μ -phase structure were to intergrow with the Cs_6K_7 structural type. Another kind of well-resolved planar defect in a crystal of μ phase is shown in Fig. 6. The white dots in a region of a defect form a zigzag row revealing the presence of an intergrowth between the μ -phase structure and three sheets of the $MgZn_2$ -type structure. The atomic arrange-

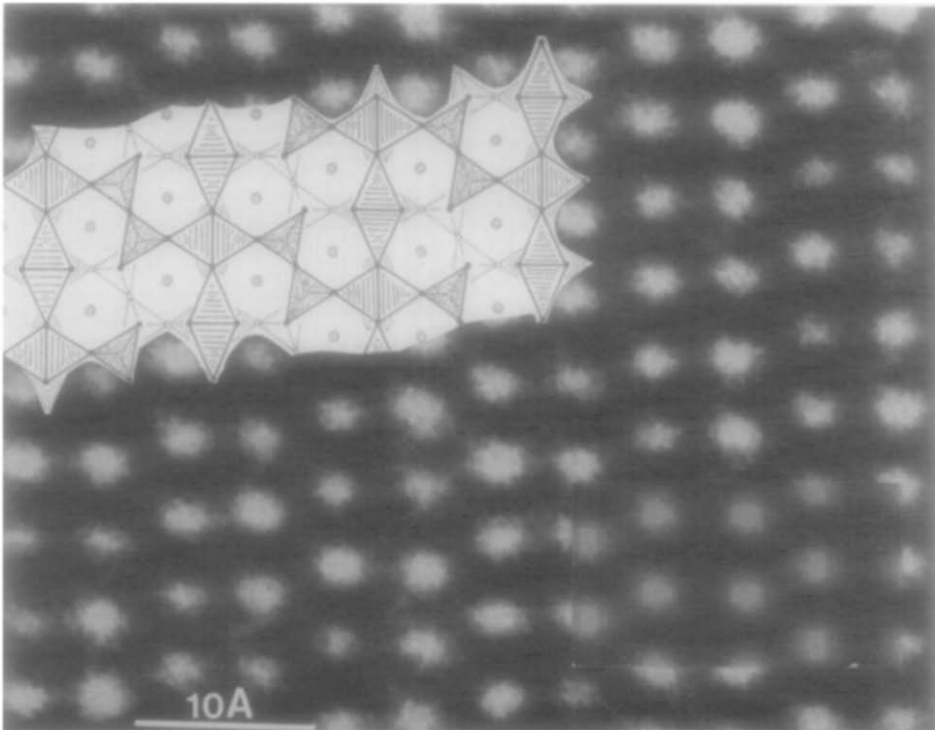


FIG. 4. CSI of a perfect $(Ni,Cr)_7Nb_6$ crystal with the μ -phase structure. The inserted calculated image was made with focus = -600 \AA and thickness = 39.56 \AA (8 slices).

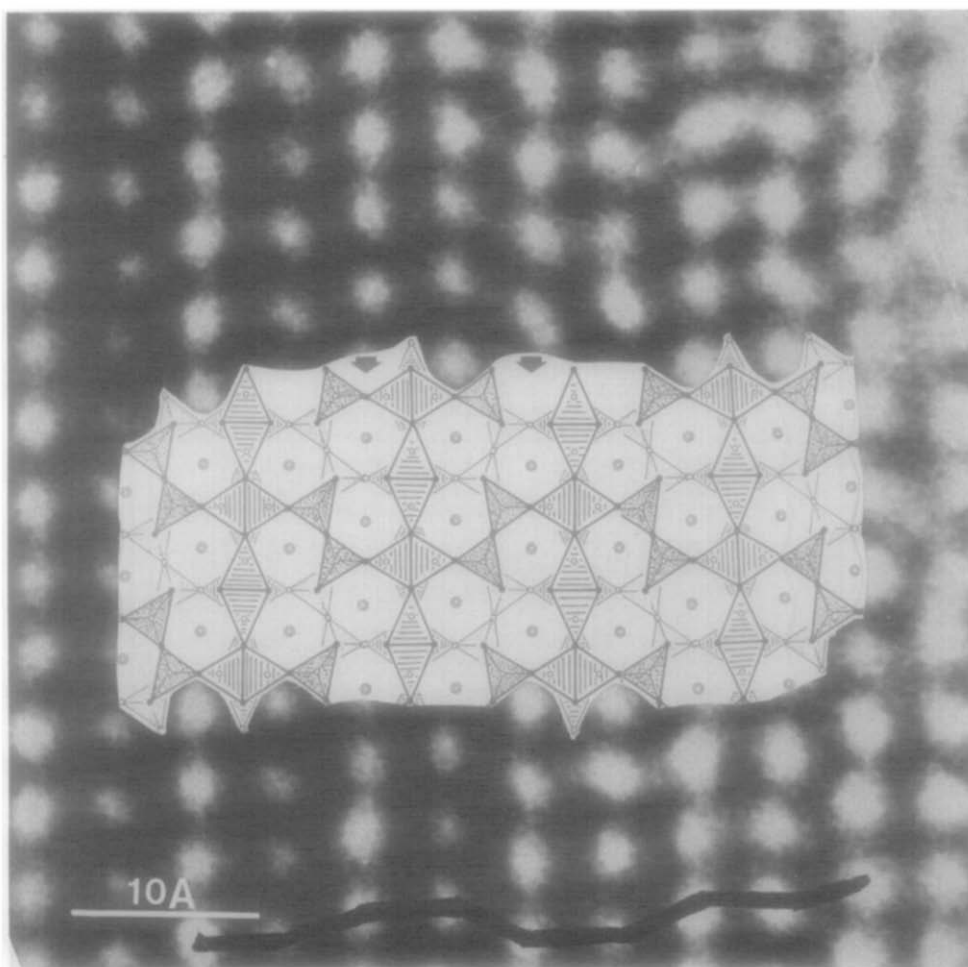


FIG. 5. Twin defects in a crystal with μ -phase structure. Arrows indicate twin-planes.

ment of the defect region derived from the image contrast is given in the inserted drawing.

Conclusions

It is clear that high-resolution electron microscopy is of great value for the investigation of the local defect structures of crystals of tetrahedrally close-packed alloys,

which cannot be determined by other indirect methods. The Friauf-Laves and μ phases studied contain different kinds of defects. We have presented models for a variety of defect structures, which were derived by a direct correlation between contrast in a high-resolution lattice image and structural features. The structure of defects can be explained as derived from chemical twinning and intergrowth operations.

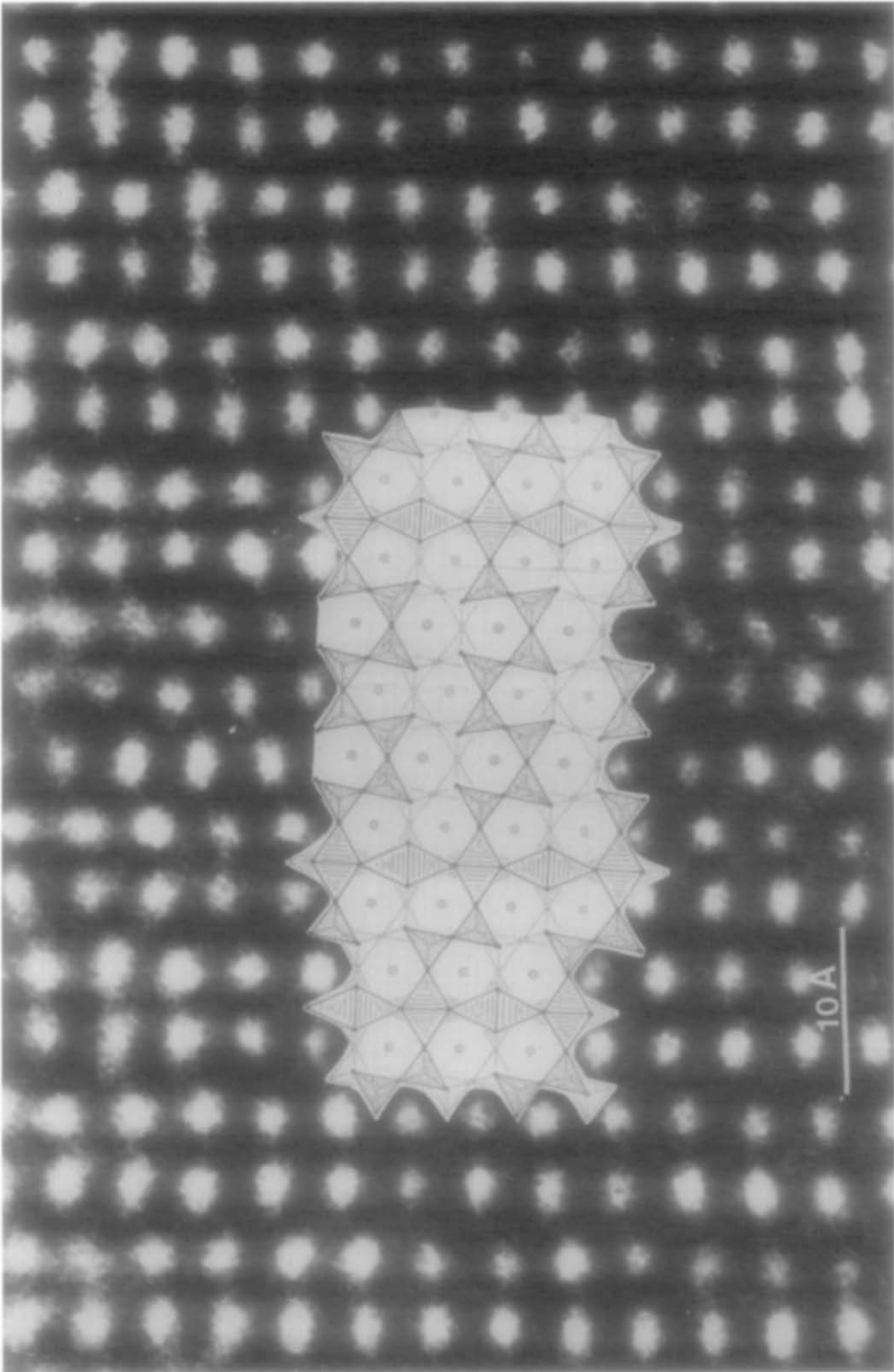


Fig. 6. Crystal with μ -phase structure intergrown with slabs with MgZn_2 structure.

Acknowledgments

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